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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/586,624	06/02/2000	Naoya Hasegawa	9281/3660 6578 EXAMINER	
75?	7590 08/16/200	1		
BRINKS HOFER GILSON & LIONE P.O. BOX 10395			BERNATZ, KEVIN M	
CHICAGO,			ART UNIT	PAPER NUMBER
			1773	
			DATE MAILED: 08/16/2004	,

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)			
Advisory Action	09/586,624	HASEGAWA, NAOYA			
Advisory Addon	Examiner	Art Unit			
	Kevin M Bernatz	1773			
The MAILING DATE of this communication appe	ars on the cover sheet with the o	correspondence address			
THE REPLY FILED 16 July 2004 FAILS TO PLACE THIS Therefore, further action by the applicant is required to average final rejection under 37 CFR 1.113 may only be either: (1) condition for allowance; (2) a timely filed Notice of Appeal Examination (RCE) in compliance with 37 CFR 1.114.	oid abandonment of this application applic	ation. A proper reply to a			
PERIOD FOR RE	EPLY [check either a) or b)]				
 a)	Advisory Action, or (2) the date set forth ater than SIX MONTHS from the mailing	g date of the final rejection.			
Extensions of time may be obtained under 37 CFR 1.136(a). The fee have been filed is the date for purposes of determining the period of fee under 37 CFR 1.17(a) is calculated from: (1) the expiration date of the control (2) as set forth in (b) above, if checked. Any reply received by the Office timely filed, may reduce any earned patent term adjustment. See 37 C	of extension and the corresponding amo the shortened statutory period for reply the later than three months after the mail	unt of the fee. The appropriate extension originally set in the final Office action; or			
1. A Notice of Appeal was filed on Appellant's 37 CFR 1.192(a), or any extension thereof (37 CFF					
2. The proposed amendment(s) will not be entered be	ecause:				
(a) they raise new issues that would require further	er consideration and/or search (s	see NOTE below);			
(b) they raise the issue of new matter (see Note b	elow);	,			
(c) they are not deemed to place the application ir issues for appeal; and/or	n better form for appeal by mate	rially reducing or simplifying the			
(d) they present additional claims without canceling NOTE:	ng a corresponding number of fi	nally rejected claims.			
3. Applicant's reply has overcome the following rejecti	ion(s):				
4. Newly proposed or amended claim(s) would canceling the non-allowable claim(s).		eparate, timely filed amendment			
5. ☐ The a) ☐ affidavit, b) ☐ exhibit, or c) ☐ request for application in condition for allowance because: See	reconsideration has been consideration Sheet.	dered but does NOT place the			
6. The affidavit or exhibit will NOT be considered becaraised by the Examiner in the final rejection.		o issues which were newly			
7. For purposes of Appeal, the proposed amendment	For purposes of Appeal, the proposed amendment(s) a) will not be entered or b) will be entered and an explanation of how the new or amended claims would be rejected is provided below or appended.				
The status of the claim(s) is (or will be) as follows:					
Claim(s) allowed: <u>none</u> .					
Claim(s) objected to: <u>none</u> .					
Claim(s) rejected: <u>1-9</u> .					
Claim(s) withdrawn from consideration: 10-14.					
8. The drawing correction filed on is a) appr	oved or b) disapproved by the	ne Examiner.			
9. Note the attached Information Disclosure Statemen					
10. Other:	/ / / / / / / / / / / / / / / / / / / /				

Continuation of 5. does NOT place the application in condition for allowance because: applicants' arguments have been considered but are not convincing. Specifically, applicants argue that Gill fails to teach that the soft magnetic "seed" layers are deposited in a recess of the free magnetic layer and that reliance upon Gill is therefore improper. The Examiner respectfully disagrees.

Applicants are reminded that a rejection under 103(a) is in view of the combined teachings of the prior art references, not whether eac individual references teaches the entire claimed subject matter. In the instant case, Lin provides clear teaching that the free magnetic layer is formed to possess recesses in the portions exterior to the track width (Figure 3 and col. 6, lines 33 - 46) even stating that "seed" layers are optional if the free layer is not extensively milled in the end regions. While Lin discloses forming ferromagnetic "seed" layers in the recessed portions, Lin fails to disclose forming these layers to a thickness exceeding the height of the free magnetic layer in the track width region. The Examiner has taken the position that it would have been obvious to determine an optimal thickness of the seed layers and that one of ordinay skill in the art would be readily apraised that the thickness could exceed the height of the free layer. Gill provides explicit evidence that the "seed" ferromagnetic layers located on the end regions between the free layer and the antiferromagnetic layer can be formed to a height greater than the surface of the free layer.

Furthermore, the Examiner notes that Gill is significantly different than Rottmeyer et al. in that Gill provides an explicit figure apparently showing recesses in the free magnetic layer. While the Examiner acknowledges applicants interpretation of the dashed lines in Figure 7 of Gill, the Examiner can find no evidence in Gill that the MPEP interpretation of "dashed lines" was adhered to. The Examiner will acknowledge that Gill is ambiguous as to whether the free layer possesses recesses, but as noted above, Lin already provides explicit teaching that the free layer can be "ion-milled extensively" to form recesses, so Gill is not required to teach that limitation. Claims 1 - 9 have been rejected under the combined teachings of Lin in view of Gill (in addition to other references).

Kenis M. Bernstz Kens M. Bernstz Primay Examina 8/9/04